PCN Number: 2018053	1007	PCN Date:	June	1, 201	18		
Title: Datasheet for OPA355-0	Q1						
Customer Contact: PCN Manager			De	ept:	Quality Services		
Change Type:							
Assembly Site	Desi	gn		Wafe	er Bump Site		
Assembly Process		Sheet		Wafer Bump Material			
		number change			Wafer Bump Process		
		Site			Wafer Fab Site		
Packing/Shipping/Labeling	Test	Process		Wafer Fab Materials			
	N:C:			Wafe	er Fab Process		
	Notific	cation Details					
Description of Change:		na an information	- nl. r	atificati	ian		
Texas Instruments Incorporated in		_	•	ouncau	1011.		
The product datasheet(s) is being The following change history prov	•		vv.				
	ides fultile	a details.					
ŢEXAS					OPA355-Q1		
INSTRUMENTS SLOS868C - DECEMBER 2013 - REVISED MAY 20							
Changes from Revision B (June 2014) to Revision C Page							
Deleted "C55" marking on pinout drawing in Pin Configuration and Functions section							
Deleted "C55" marking on pinout drawing in Pin Configuration and Functions section							
Deleted storage temperature range from ESD Ratings table and moved to Absolute Maximum Ratings table							
Changed title of Handling Ratings table to ESD Ratings table							
Added Recommended Operating Conditions table							
Added Functional Block Diagram							
Deleted "Independent enable pins are a Enable Function section							
Deleted Input and ESD Protection subsection in Feature Description section							
Added Device Functional Modes section							
Added Typical Applications section to Application and Implementation section							
Added Design Requirements subsection to Typical Applications section							
Added Detailed Design Procedure subsection to Typical Application section							
Added application curves to the Typical Application section							
 Added High-Impedance Sensor Interface, Driving ADCs, and Active Filter subsections to Typical Application section 16 							
Added Power Supply Recommendations section							
Added layout example image to Layout	section				19		
The datasheet number will be cha	nging.						
Device Family		Change From:		Chang	ge To:		
OPA355-Q1		SLOS868B		SLOS	868C		
These changes may be reviewed a	at the data	sheet links provide	d.	•			
,							
http://www.ti.com/product/OPA3	55-Q1						
Reason for Change:							
To accurately reflect device chara							
Anticipated impact on Fit, For							
No anticipated impact. This is a spot to the actual device.	pecification	change announcer	ment o	only. Th	nere are no changes		
Changes to product identificat	ion result	ing from this PCN	N:				
None.							
Product Affected:							
OPA355ODBVRO1							

For questions regarding this notice, e-mails can be sent to the regional contacts shown below or your local Field Sales Representative.

Location	E-Mail
USA	PCNAmericasContact@list.ti.com
Europe	PCNEuropeContact@list.ti.com
Asia Pacific	PCNAsiaContact@list.ti.com
Japan	PCNJapanContact@list.ti.com